

- Lin-Reddy algebra, 424
- Lindbloom, 624
- line, 267
- line justification, 162
- line-delay fault, 61, 62
- line-delay test, 428
- linear analog fault simulation, 395
- linear depreciation, 38, 54
- linear feedback shift register, 300, 495, 498, 503, 519
- linear phase shifter, 512
- linear quantization error, 364
- linear system, 516
- linkage pin, 571
- linked fault, 278
- Linn, 626
- logic analyzer software, 28
- logic cone, 160
- logic design, 7
- logic error, 259
- logic level, 91, 92, 132, 148
- logic transformation fault, 180
- logical fault, 63, 263
- Lombardi, 621
- long-run production, 38
- loop, 233
- loopback circuit, 527
- loopback test, 540, 581
- loss variability test, 372
- low-pass case, 353
- LRU (lowest replaceable unit), 596
- LSSD, 50, 468, 477, 524
- LTX Fusion tester, 28

- M1, 581
- M2, 581
- macro test, 609, 610
- macroeconomics, 36
- Mahoney, 309, 622
- maintenance log, 601
- maintenance test, 48
- Malaiya, 61, 446, 626
- Maloney, 627
- Maly, 627
- mandatory assignment, 197
- Manning, 465, 625
- manufacturing test, 17, 59
- Mao, 444, 448, 449
- MARCH A test, 281, 285
- MARCH B test, 281, 285
- MARCH C and Delay test, 296
- MARCH C test, 281, 296, 532, 539
- MARCH C– test, 285, 304
- march element, 263
- MARCH G test, 295
- march test, 263
- MARCH X test, 285
- MARCH Y test, 285
- MARCHING 1/0 test, 281
- marginal product, 39

- Marlett, 219
- MARS hardware accelerator, 116
- mass production, 41
- master, 212
- material defect, 58
- material grains, 260
- matrix period, 504
- MATS test, 281, 285
- MATS+ and Delay test, 296
- MATS+ test, 263, 285, 296, 533, 536
- MATS++ test, 285, 304
- matured process, 46
- Maunder, 623
- maximal element tolerance, 401
- maximal length LFSR, 503
- maximum clock rate, 323
- maximum recursion depth, 201
- maximum relative variation, 403
- Maxwell, 441, 447
- Mazumder, 247, 626, 628
- McAnney, 624
- McCluskey, 54, 130, 502, 517, 528, 621
- MCM, 605
- McMillan, 626
- MDCCS, 249
- Mealy and Moore machines, 271
- mean, 360
- measured distortion, 376
- measurement, 315
- measurement error, 315, 386, 577
- measurement tolerance, 407
- measurement uncertainty, 360
- memory address scrambling, 534
- memory BIST, 529, 543
- memory cell, 258
- memory parametric testing, 301
- memory system bus burnout, 567
- memory width, 258
- MEMS, 259, 310
- MEMS part, 613
- Menon, 78, 111, 112, 621
- Mercer, 197, 204, 428, 628
- metal migration, 14
- Metze, 465, 625
- MFVS, 481
- micro electro-mechanical system, 259, 310
- micro-strip probe card, 299
- microeconomics, 35
- microprocessor clock rate, 9
- microprocessor core, 606
- microprocessor test, 10, 60, 62, 157, 158, 248, 598
- Miczko, 621
- Miller capacitance, 591
- minimal element tolerance, 401
- minimum feedback vertex set, 481
- minimum relative variation, 403
- minmax-delay simulator, 100
- misloaded component, 577
- MISR, 300, 499, 516